

**INFORMATION  
DISCLOSURE  
CITATION**

Applicant: Kevin LANCON, et al  
 Ser.No.: 10/675 207 Filed : September 30, 2003  
 Conf. No.: 9935 Atty.Ref.: Flowserve C-94  
 Group : 2859

JUN 28 2004

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## U.S. PATENT DOCUMENTS

Examiner Initials*	Document Number	Date	Name	Class	Sub Class	Filing Date
SOB	AA 3 921 435	Nov 1975	Howard	—	—	
	AB 4 691 276	Sep 1987	Miller, et al	—	—	
	AC 4 781 064	Nov 1988	Yates	—	—	
	AD 4 854 162	Aug 1989	Yerace, et al	—	—	
	AE 5 041 989	Aug 1991	Kataoka, et al	—	—	
	AF 5 050 092	Sep 1991	Perry	—	—	
	AG 5 115 406	May 1992	Zatezalo, et al	—	—	
	AH 5 381 692	Jan 1995	Winslow, et al	—	—	
	AI 5 533 413	Jul 1996	Kobayashi, et al	—	—	
	AJ 5 628 229	May 1997	Krone, et al	—	—	
	AK 5 691 707	Nov 1997	Smith, et al	—	—	
	AL 5 762 342	Jun 1998	Kakabaker, et al	—	—	
	AM 5 992 237	Nov 1999	McCarty, et al	—	—	
	AN 6 006 164	Dec 1999	McCarty, et al	—	—	
↓	AO 6 065 345	May 2000	Holenstein, et al	—	—	

## FOREIGN PATENT DOCUMENTS

Document Number	Date	Country	Class	Sub Class	Translation Yes No
AP					

## OTHER DOCUMENTS (Including Author, Title, Date, Pages, Etc.)

SOB	AR 1	Rockwell International Corporation, ENTEK, "The Ten Most Common Reasons Why Oil Analysis Programs Fail and the Strategies That Effectively Overcome Them", Publication No. ENOAS-AT401A-EN-P, March 2001, pp. 1-12				
SOB	AS 1	ENTEK IRD and Flowserve Flow Solutions Division, Condition Data Point Monitoring™, "Monthly Report - Complex 3/4 Machines", September 27, 2002, pp. 1-7				

EXAMINER

Stanley J. Pancherz, Jr.

DATE CONSIDERED

28 SEPT 2004

\*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.

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SOP	82 737	Jul 2000	Williamson, et al	—	—	
	AB 6 161 962	Dec 2000	French, et al	—	—	
	AC 6 202 491 B1	Mar 2001	McCarty, et al	—	—	
	AD 6 208 953 B1	Mar 2001	Milek, et al	—	—	
	AE 6 236 328 B1	May 2001	Smith, et al	—	—	
	AF 6 241 383 B1	Jun 2001	Feller, et al	—	—	
	AG 6 260 004 B1	Jul 2001	Hays, et al	—	—	
	AH 6 271 761 B1	Aug 2001	Smith, et al	—	—	
	AI 6 289 735 B1	Sep 2001	Dister, et al	—	—	
	AJ 6 297 742 B1	Oct 2001	Canada, et al	—	—	
	AK 6 330 525 B1	Dec 2001	Hays, et al	—	—	
	AL 6 332 116 B1	Dec 2001	Qian, et al	—	—	
	AM 6 360 616 B1	Mar 2002	Halliday, et al	—	—	
	AN 6 425 293 B1	Jul 2002	Woodroffe, et al	—	—	

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Document Number	Date	Country	Class	Sub Class	Translation Yes No
AP					

## OTHER DOCUMENTS (Including Author, Title, Date, Pages, Etc.)

SOP	AR 2	ENTEK, Rockwell Automation, Integrated Condition Monitoring Solutions, "Enwatch™ Online Surveillance System" brochure, Publication No. ENOLS-TD302A-EN-P, March 2002 (6 Pages)
SOP	AS 2	ENTEK, Rockwell Automation, Integrated Condition Monitoring Solutions, "Enpac™ Family" brochure, Publication No. ENPOR-TD101B-EN-P, March 2002 (6 Pages)
SOP	AT 2	ENTEK, Rockwell Automation, "ENTEK XM™ - Machine Monitoring and Protection System" brochure, Publication No. ENMON-PP105A-EN-P, September 2002 (4 Pages)

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Stanley T. Prushnic Jr.

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